

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1210	Apr-97	9710 C1	HYUNDAI	DL650775AAE	3.0μ OX/NI	16 SOIC

**STRESS/JOB NO.**

**READPOINT  
(Sample Size/No. of Fails)**

Preconditioning (P/C):  
HTC Vapor Phase  
P-19646

Electrical      Cum %  
235/0              0.0%

Sonoscan  
P-19693

Post Vapor Phase  
4/2  
F1

Infant / High Voltage Life  
125°C, 7.0 V.  
P-19694, P-19765

48 Hr    336 Hr    1KHr              \*Failure Rate  
231/0    77/0

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle  
-55°C to +125°C  
P-19766

300 ~      1K ~              Cum %  
39/0

Biased Moisture  
85°C/85% RH, 5.5 V.  
P-19767

274 Hr      959 Hr              Cum %  
77/0

Autoclave  
121°C/100% RH, 2 Atmos  
P-19768

96 Hr              Cum %  
38/0              0.0%

**Failure Mode**

F1: 2-Delamination

**Failure Analysis**

In process